

# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

Applied Image Inc. 1653 East Main Street Rochester, NY 14609

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

### **CALIBRATION**

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at <a href="www.anab.org">www.anab.org</a>.

Jason Stine, Vice President

Expiry Date: 30 October 2025 Certificate Number: AC-2818





### **SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017**

### **Applied Image Inc.**

1653 East Main Street Rochester, NY 14609 Gary Reif 585-482-0300 ext. 230

### **CALIBRATION**

Valid to: October 30, 2025 Certificate Number: AC-2818

### **Length – Dimensional Metrology**

Version 006 Issued: September 6, 2024

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Single Axis Length Non-Contact <sup>1</sup>	Up to 200 μm (200 to 400) μm (400 to 800) μm (800 to 1 600) μm	0.43 μm 0.73 μm 1.3 μm 1.5 μm	Filar Microscope
	Up to 127 mm	0.29 μm	Laser-based Measuring Machine
	(0.8 to 400) mm	$(2.3 + 0.008L) \mu m$	CMM
	(401 to 1 200) mm	$(15 + 0.051L) \mu m$	Coordinatograph
	Up to 25.4 mm (25.4 to 75) mm	2.4 μm 4.5 μm	Micrometers
	Up to 150 mm	32 μm	Caliper
Dual Axis Length Non-Contact <sup>1</sup>	Up to 127 mm x 127 mm	0.42 μm	Laser-based Measuring Machine
Length Aspect of Bar Code Measurement <sup>1</sup>	(3 to 200) mils	$(0.051 + 0.000 \ 25L)$ mils	Automated Bar Code Verification System
	(0.2 to 5) mm	$(1.3 + 0.25L) \mu m$	(Judge)
Angular Measurement <sup>4</sup>	(0 to 180)°	0.001 8°	Coordinate Measuring Machine





#### **Photometry and Radiometry**

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Spectral Reflection Aspect of Bar Code Measurement <sup>2,3</sup>	(0.25 to 100) %R 660 nm	(0.35 + 0.014R) %R	Automated Bar Code Verification System (Judge)
45°:0° or 0°:45° Spectral Reflection Photometry <sup>3</sup> (Status A Density)	(V Filter)	0.011 D 0.033 D 0.012 D 0.034 D 0.009 5 D 0.026 D 0.009 4 D 0.031 D	Color Reflection Densitometer
45°:0° or 0°:45° Spectral Reflection Photometry <sup>2,3</sup>	(0.25 to 100) %R 660 nm	(0.066 + 0.007R) %R	Spectral Reflectometer
Spectral Transmission Photometry <sup>2,3</sup>	Up to 100 %T (250 to 400) nm (401 to 700) nm (701 to 900) nm (901 to 1 000) nm	(0.15 + 0.004 1T) %T (0.22 + 0.000 66T) %T (0.4 - 0.000 72T) %T (0.67 + 0.002 7T) %T	Transmission Spectro-photometer
Transmission Density <sup>3</sup> (Orthochromatic Filter)	Up to 3.7 D (3.701 to 4.5) D	0.025 D 0.059 D	Transmission Densitometer

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (*k*=2), corresponding to a confidence level of approximately 95%.

#### Notes:

- 1. L = length in mils or mm.
- 2. R = value in % R; T = value in % T.
- 3. The following are non-SI terms: %T is percent transmission; %R is the percent reflectance; and D is the optical density.
- 4. The angle is determined by the measurement of two points on a line in the x-y plane. The x-y values are used to calculate the angle using the arctan(x-y). The distance between the two points affect the uncertainty as indicated. L is the length of the measured line in mm.
- 5. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-2818.

Jason Stine, Vice President

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